



STD22NM20N

N-CHANNEL 200V - 0.088Ω - 22A DPAK ULTRA LOW GATE CHARGE MDmesh™ II MOSFET

Table 1: General Features

TYPE	V _{DSS}	R _{DS(on)}	I _D
STD22NM20N	200 V	< 0.105 Ω	22 A

- WORLDWIDE LOWEST GATE CHARGE
- TYPICAL R_{DS(on)} = 0.088 Ω
- HIGH dv/dt and AVALANCHE CAPABILITIES
- LOW INPUT CAPACITANCE
- LOW GATE RESISTANCE

DESCRIPTION

This 200V MOSFET with a new advanced layout brings all unique advantages of MDmesh technology to lower voltages. The device exhibits world-wide lowest gate charge for any given on-resistance. Its use is therefore ideal as primary switch in isolated DC-DC converters for Telecom and Computer applications. Used in combination with secondary-side low-voltage STripFET™ products, it contributes to reducing losses and boosting efficiency.

APPLICATIONS

The MDmesh™ family is very suitable for increasing power density allowing system miniaturization and higher efficiencies

Figure 1: Package

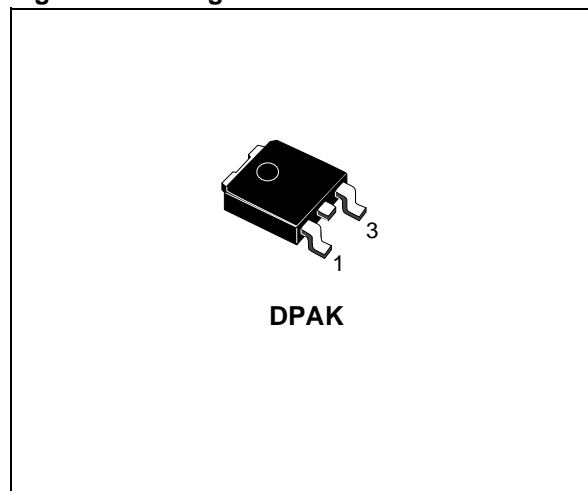


Figure 2: Internal Schematic Diagram

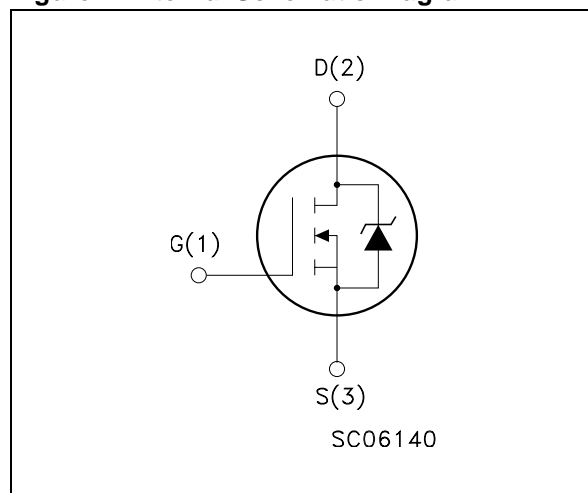


Table 2: Order Codes

SALES TYPE	MARKING	PACKAGE	PACKAGING
STD22NM20NT4	D22NM20N	DPAK	TAPE & REEL

Table 3: Absolute Maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source Voltage ($V_{GS} = 0$)	200	V
V_{DGR}	Drain-gate Voltage ($R_{GS} = 20\text{ k}\Omega$)	200	V
V_{GS}	Gate- source Voltage	± 20	V
I_D	Drain Current (continuous) at $T_C = 25^\circ$	22	A
	Drain Current (continuous) at $T_C = 100^\circ$	13.7	A
$I_{DM} (*)$	Drain Current (pulsed)	88	A
P_{TOT}	Total Dissipation at $T_C = 25^\circ\text{C}$	100	W
	Derating Factor	0.8	W/ $^\circ\text{C}$
$dv/dt (2)$	Peak Diode Recovery voltage slope	14	V/ns
T_j	Storage Temperature	150	$^\circ\text{C}$
T_{stg}	Max Operating Junction Temperature	-65 to 150	$^\circ\text{C}$

(*) $I_{SD} \leq 22\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$, $V_{DD} = 80\% V_{(BR)DSS}$

Table 4: Thermal Data

$R_{thj-case}$	Thermal Resistance Junction-case Max	1.25	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal Resistance Junction-ambient Max	100	$^\circ\text{C}/\text{W}$
$R_{thj-ambT_l}$	Thermal Resistance Junction-pcb (*)	43	$^\circ\text{C}/\text{W}$
	Maximum Lead Temperature For Soldering Purpose	275	$^\circ\text{C}$

(*) When mounted on 1 inch² FR-4 board, 2 oz Cu, $t \leq 10\text{ sec}$

Table 5: Avalanche Characteristics

Symbol	Parameter	Max Value	Unit
I_{AS}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max)	22	A
E_{AS}	Single Pulse Avalanche Energy (starting $T_j = 25^\circ\text{C}$, $I_D = 22\text{ A}$, $V_{DD} = 50\text{ V}$)	380	mJ

ELECTRICAL CHARACTERISTICS ($T_{CASE} = 25^{\circ}\text{C}$ UNLESS OTHERWISE SPECIFIED)**Table 6: On/Off**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown Voltage	$I_D = 1\text{mA}$, $V_{GS} = 0$	200			V
I_{DSS}	Zero Gate Voltage Drain Current ($V_{GS} = 0$)	$V_{DS} = \text{Max Rating}$ $V_{DS} = \text{Max Rating}$, $T_C = 125^{\circ}\text{C}$			1 10	μA μA
I_{GSS}	Gate-body Leakage Current ($V_{DS} = 0$)	$V_{GS} = \pm 20\text{V}$			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\ \mu\text{A}$	3.5	4.2	5	V
$R_{DS(on)}$	Static Drain-source On Resistance	$V_{GS} = 10\text{V}$, $I_D = 11\ \text{A}$		0.088	0.105	Ω

Table 7: Dynamic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g_{fs} (2)	Forward Transconductance	$V_{DS} = 15\ \text{V}$, $I_D = 11\ \text{A}$		8		S
C_{iss} C_{oss} C_{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25\text{V}$, $f = 1\ \text{MHz}$, $V_{GS} = 0$		800 330 130		pF pF pF
$C_{oss\ eq.}^{(**)}$	Equivalent Output Capacitance	$V_{GS} = 0\ \text{V}$, $V_{DS} = 0\ \text{V to } 400\ \text{V}$		225		pF
R_G	Gate Input Resistance	$f = 1\text{MHz}$ Gate DC Bias = 0 Test Signal Level = 20 mV Open Drain		5		Ω
$t_{d(on)}$ t_r $t_{r(Voff)}$ t_f	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$V_{DD} = 100\ \text{V}$, $I_D = 11\ \text{A}$ $R_G = 4.7\ \Omega$ $V_{GS} = 10\ \text{V}$ (see Figure 15)		40 15 40 11		ns ns ns ns
Q_g Q_{gs} Q_{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 100\ \text{V}$, $I_D = 20\ \text{A}$, $V_{GS} = 10\ \text{V}$ (see Figure 19)		32 6 25	50	nC nC nC

(**) $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 8: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD} I_{SDM} (1)	Source-drain Current Source-drain Current (pulsed)				22 88	A A
V_{SD} (2)	Forward On Voltage	$I_{SD} = 20\ \text{A}$, $V_{GS} = 0$			1.3	V
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 20\ \text{A}$, $di/dt = 100\ \text{A}/\mu\text{s}$ $V_{DD} = 100\text{V}$, $T_j = 25^{\circ}\text{C}$ (see test circuit, Figure 17)		160 960 128		ns μC A
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 20\ \text{A}$, $di/dt = 100\ \text{A}/\mu\text{s}$ $V_{DD} = 100\text{V}$, $T_j = 150^{\circ}\text{C}$ (see test circuit, Figure 17)		225 1642 15		ns μC A

(1) Pulse width limited by safe operating area.

(2) Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %

Figure 3: Safe Operating Area

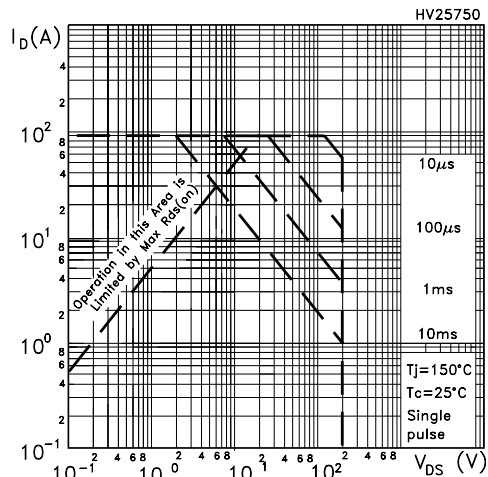


Figure 4: Output Characteristics

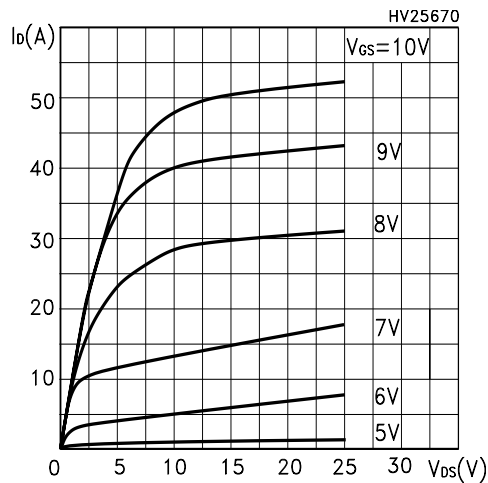


Figure 5: Transconductance

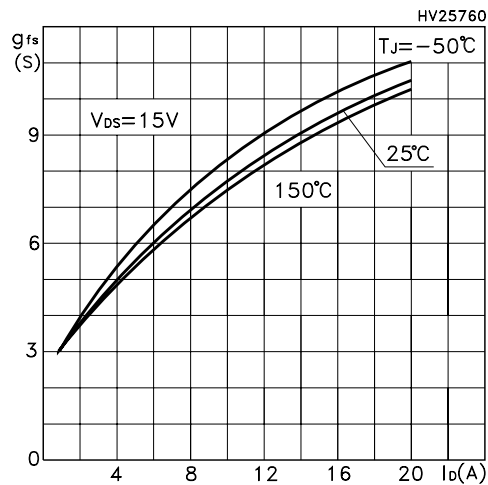


Figure 6: Thermal Impedance

Figure 7: Transfer Characteristics

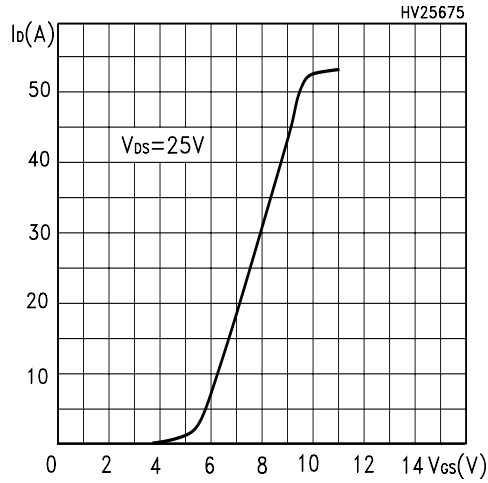


Figure 8: Static Drain-source On Resistance

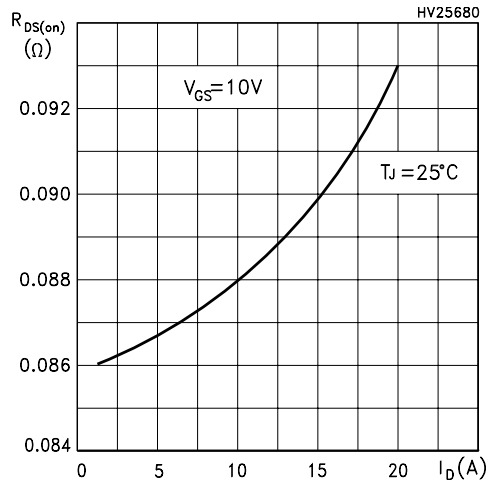
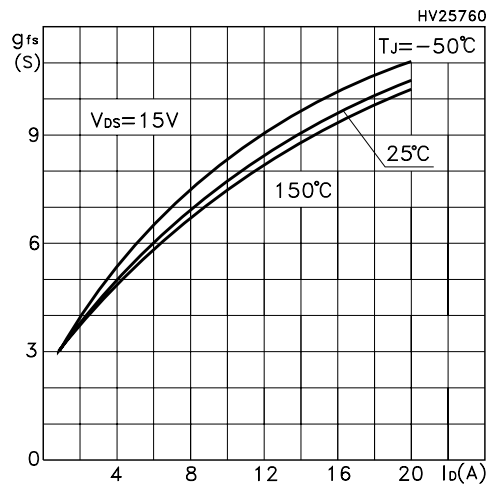


Figure 9: Gate Charge vs Gate-source Voltage

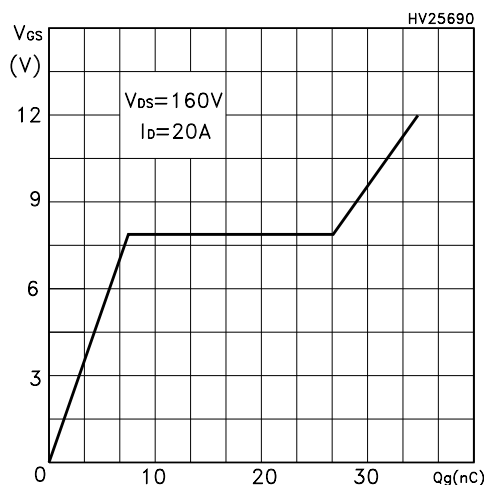


Figure 10: Normalized Gate Threshold Voltage vs Temperature

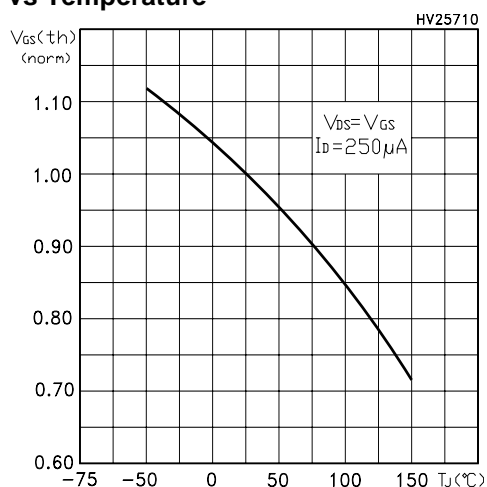


Figure 11: Source-Drain Diode Forward Characteristics

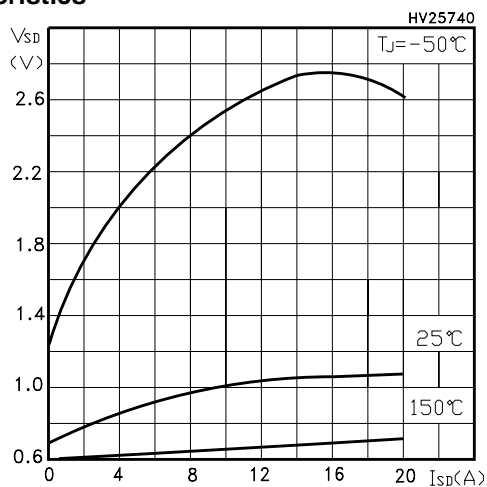


Figure 12: Capacitance Variations

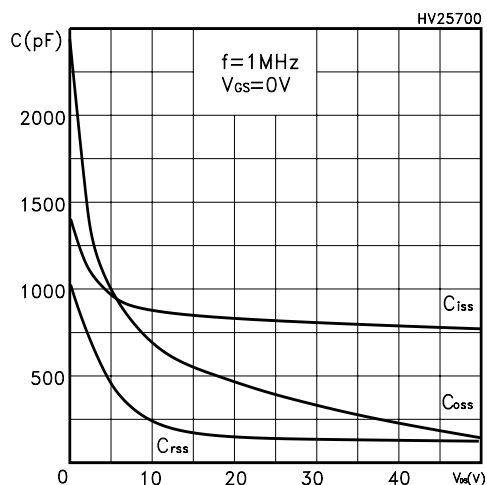


Figure 13: Normalized On Resistance vs Temperature

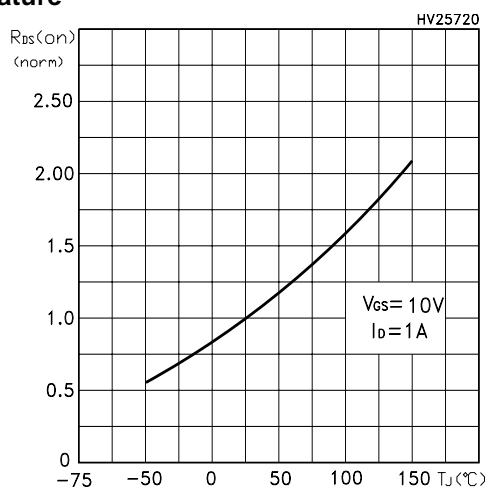


Figure 14: Normalized BVdss vs Temperature

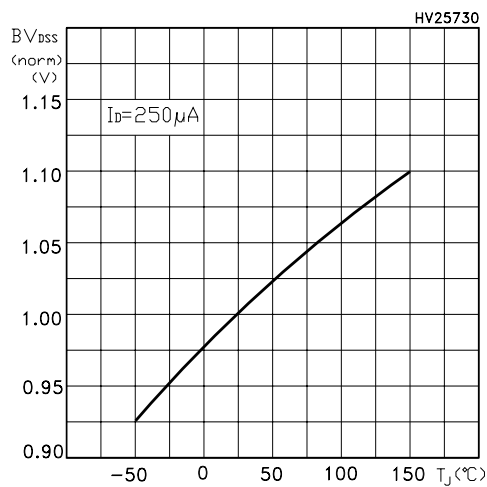


Figure 15: Unclamped Inductive Load Test Circuit

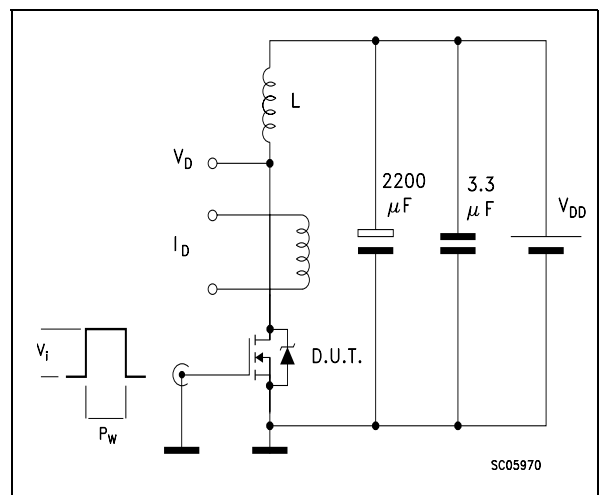


Figure 16: Switching Times Test Circuit For Resistive Load

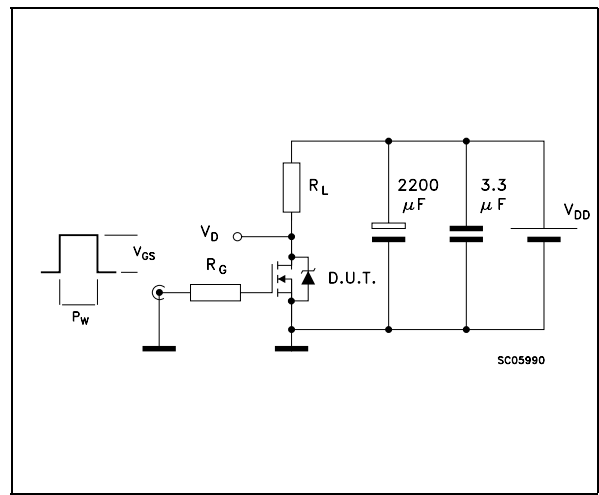


Figure 17: Test Circuit For Inductive Load Switching and Diode Recovery Times

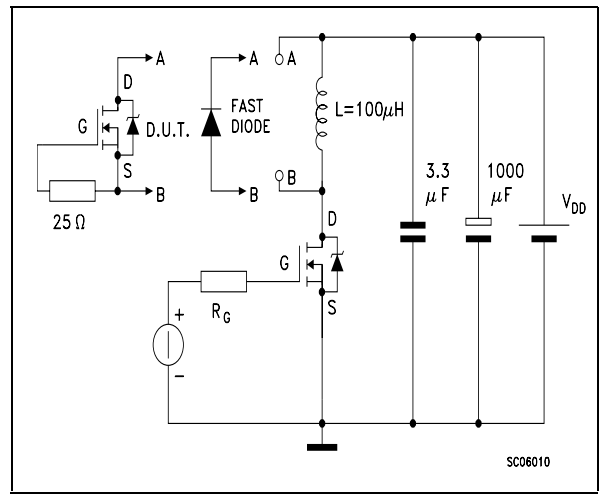


Figure 18: Unclamped Inductive Waferform

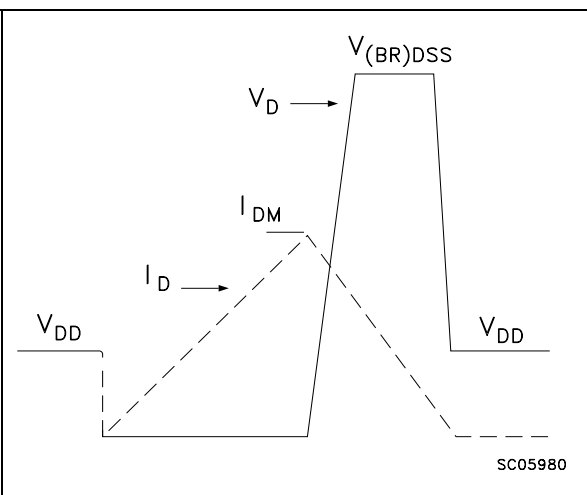
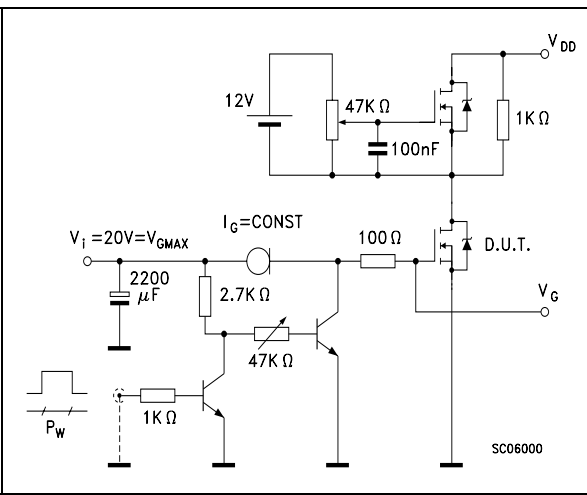
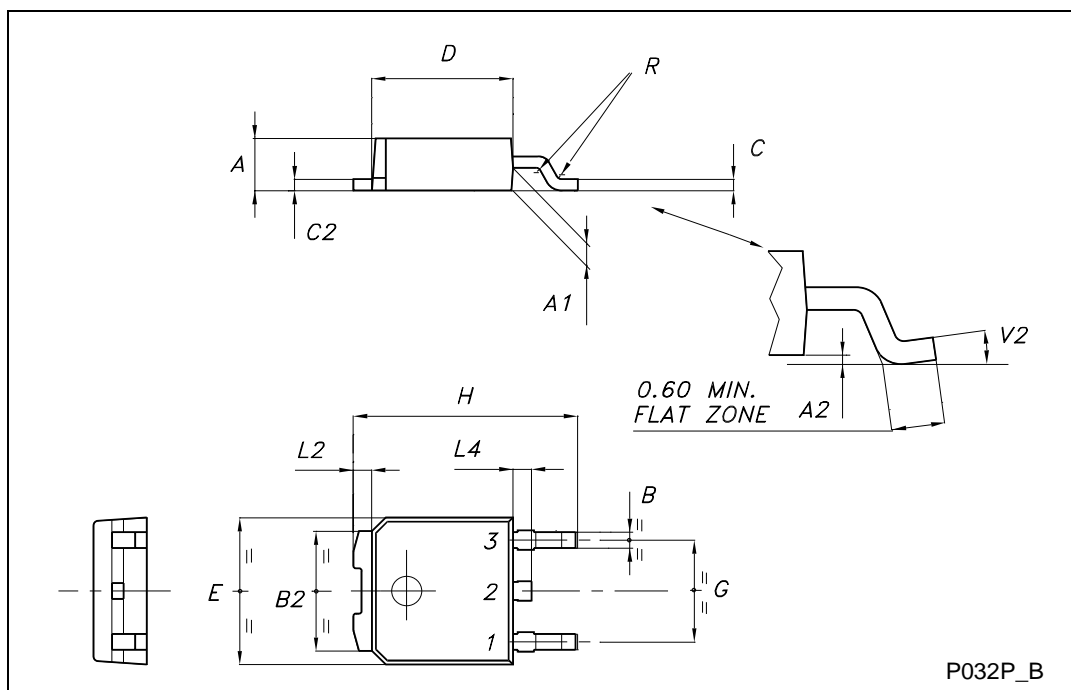


Figure 19: Gate Charge Test Circuit

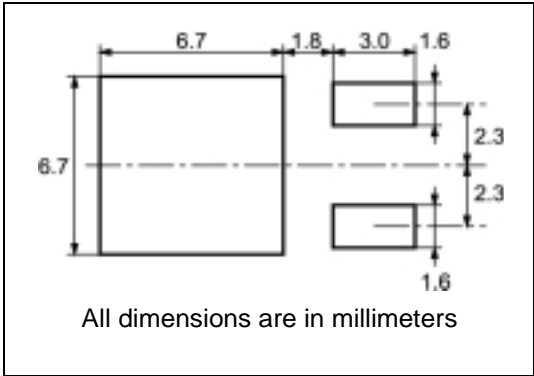


TO-252 (DPAK) MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	2.20		2.40	0.087		0.094
A1	0.90		1.10	0.035		0.043
A2	0.03		0.23	0.001		0.009
B	0.64		0.90	0.025		0.035
B2	5.20		5.40	0.204		0.213
C	0.45		0.60	0.018		0.024
C2	0.48		0.60	0.019		0.024
D	6.00		6.20	0.236		0.244
E	6.40		6.60	0.252		0.260
G	4.40		4.60	0.173		0.181
H	9.35		10.10	0.368		0.398
L2		0.8			0.031	
L4	0.60		1.00	0.024		0.039
V2	0°		8°	0°		0°



DPAK FOOTPRINT



TAPE AND REEL SHIPMENT

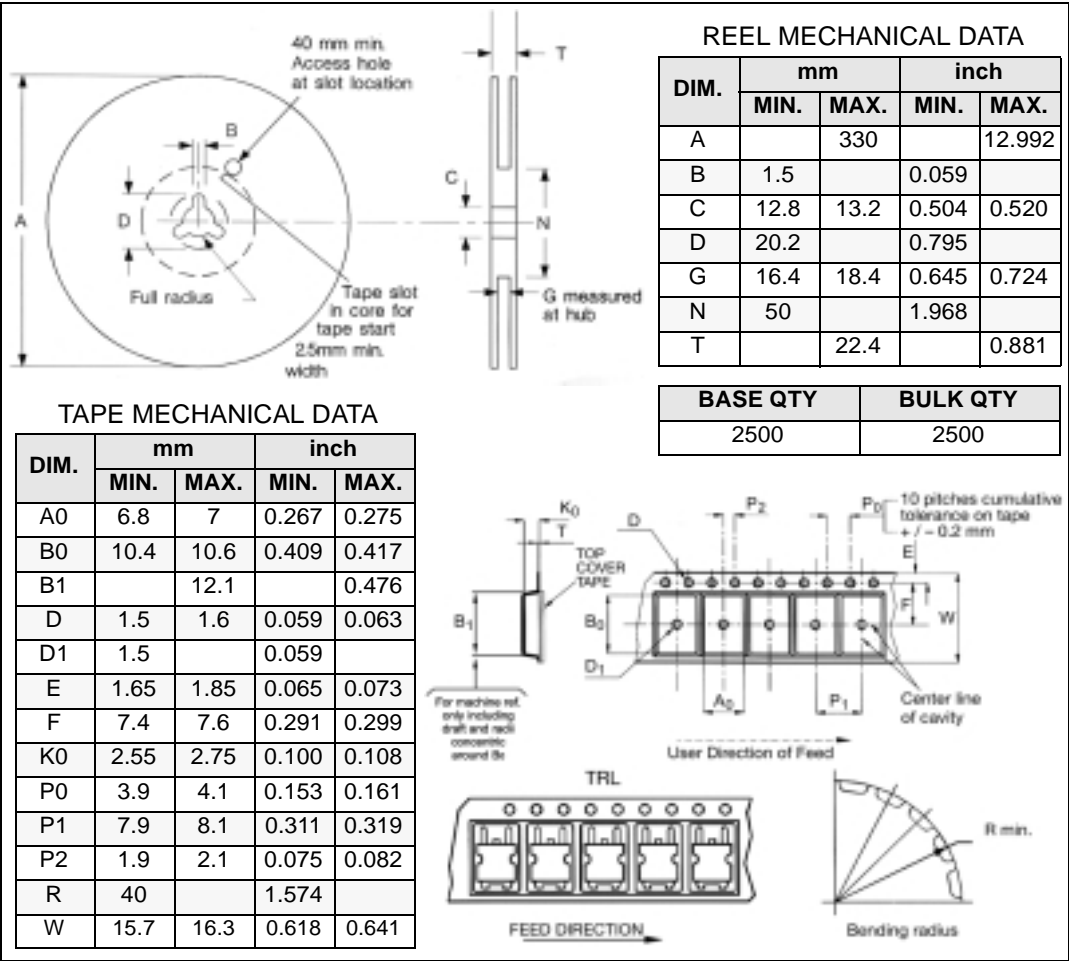


Table 9: Revision History

Date	Revision	Description of Changes
31-May-2004	1	First Release.
15-Mar-2005	2	Update version.
09-May-2005	3	Complete version.
09-Jun-2005	4	New update

Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

The ST logo is a registered trademark of STMicroelectronics

All other names are the property of their respective owners

© 2005 STMicroelectronics - All Rights Reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America